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3	7.	The method of claim 5, further comprises the step of toggling the clock for reading out
4		the clock count.
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6	8.	The method of claim 1, further comprising the step of communicating with a JTAG
7		interface.
8		
9	9.	The method of claim 4, further comprises the step of communicating with a JTAG
1 0		interface.
12	10.	An apparatus to detect process variations comprising:
<u>1</u> 3		a first circuit to select a clock;
14		a second circuit connected to the first circuit to generate at least one clock count; and
10 11 12 13 14 15 16		a third circuit connected to the first circuit to output a result of the clock count.
1 7	11.	The apparatus of claim 10, wherein the first circuit comprises:
18		a scan signal; and
19		a clock signal, wherein the scan signal and the clock signal turn on at least one clock.
20		
21	12.	The apparatus of claim 11, wherein the first circuit further comprises:
22		a reset signal; and
23		an enable signal, wherein the enable signal enables the at least one clock.
24		
25	13.	The apparatus of claim 11, wherein the clock signal is toggled for a period of time.
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27	14.	The apparatus of claim 13, wherein the second circuit further comprises outputting a
28		count of the toggle.

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3	15.	The apparatus of claim 14, wherein the third circuit comprises:
4		a counter; and
5		a scan chain, wherein the scan chain is connected to the counter.
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7	16.	The apparatus of claim 15, wherein the count is input to the counter.
8		
9	17.	The apparatus of claim 15, wherein the reset signal is input to the counter.
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	18.	The apparatus of claim 16, wherein the scan chain further comprises a read signal,
12		wherein the read signal reads the count into the scan chain.
13		
14	19.	The apparatus of claim 18, wherein the clock signal is toggled to read out the count
15		from the scan chain.
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1.7 1.7	20.	The apparatus of claim 10, wherein communicates with a JTAG interface.
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